L Number	Hits	Search Text	DB	Time stamp
1	0	09/856982	USPAT;	2003/05/16 15:48
			US-PGPUB;	
			EPO; JPO;	1
			DERWENT; IBM TDB	
2	7	"6292259"	USPAT;	2003/05/16 16:03
			US-PGPUB;	1
·	'		EPO; JPO;	
			DERWENT;	
3	8540	inanaatta maayafa	IBM_TDB	
•	8340	inspect\$3 near9 wafer	USPAT;	2003/05/16 16:05
			US-PGPUB; EPO; JPO;	
		i	DERWENT;	
		1	IBM TDB	
	6	(inspect\$3 near9 wafer) and multiple near1	USPAT;	2003/05/16 16:07
		optics	US-PGPUB;	1
•			EPO; JPO;	i
			DERWENT;	İ
	0	linenest\$2 nearD unfeat and multiple	IBM_TDB	1
	U	(inspect\$3 near9 wafer) and multiple near light near optics	USPAT;	2003/05/16 16:08
		right hear operes	US-PGPUB; EPO; JPO;	
			DERWENT;	
			IBM TDB	
	587	(inspect\$3 near9 wafer) and occurrence	USPAT;	2003/05/16 16:21
;			US-PGPUB;	
			EPO; JPO;	
İ			DERWENT;	
!	94	(lingnost\$2 noama union) and	IBM_TDB	
		((inspect\$3 near9 wafer) and occurrence) and scattered and reflected	USPAT;	2003/05/16 16:09
		and scattered and refrected	US-PGPUB;	
•	i		EPO; JPO; DERWENT;	
1			IBM TDB	
ì	0	(((inspect\$3 near9 wafer) and occurrence)	USPAT;	2003/05/16 16:10
	1	and scattered and reflected) and ratio	US-PGPUB;	
i	<u> </u>	near6 (light near optics)	EPO; JPO;	
:	1		DERWENT;	
:	63 1	(((inspect\$3 near9 wafer) and occurrence)	IBM_TDB	2002/05/26 26 26
	05 -	and scattered and reflected) and ratio and	USPAT; US-PGPUB;	2003/05/16 16:10
	i	determin\$4	EPO; JPO;	!
			DERWENT;	
'			IBM TDB	
	2	((((inspect\$3 near9 wafer) and occurrence)	USPĀT;	2003/05/16 16:10
		and scattered and reflected) and ratio and	US-PGPUB;	1
:		determin\$4) and 356/237.3	EPO; JPO;	1
			DERWENT;	1
:	5	((((inspect\$3 near9 wafer) and occurrence)	IBM_TDB USPAT;	2003/05/16 16:10
į		and scattered and reflected) and ratio and	US-PGPUB;	2003/03/16 16:10
1		determin\$4) and 356/237.4	EPO; JPO;	1 1
!			DERWENT;	
	· !		IBM TDB	
	0,	((((inspect\$3 near9 wafer) and occurrence)	USPAT;	2003/05/16 16:10
		and scattered and reflected) and ratio and	US-PGPUB;	
	:	determin\$4) and 356/237.6	EPO; JPO;	
		;	DERWENT;	
	3	((((inspect\$3 near9 wafer) and occurrence)	IBM_TDB USPAT;	2003/05/16 16:11
	3 !	and scattered and reflected) and ratio and	US-PGPUB;	2003/03/10 10:11
· · · · · · · · · · · · · · · · · · ·		determin\$4) and 382/\$.ccls.	EPO; JPO;	
!			DERWENT;	
			IBM TDB	
	6 '	((((inspect\$3 near9 wafer) and occurrence)	USPAT;	2003/05/16 16:12
		and scattered and reflected) and ratio and		
		determin\$4) and 356/237.1	EPO; JPO;	
			DERWENT;	1
			IBM TDB	

11	7	((((inspect\$3 near9 wafer) and occurrence) and scattered and reflected) and ratio and determin\$4) and 356/237.2		2003/05/16 16:13
14	8	((((inspect\$3 near9 wafer) and occurrence) and scattered and reflected) and ratio and determin\$4) and 356/237.5	EPO; JPO; DERWENT;	2003/05/16 16:14
16	38	((((inspect\$3 near9 wafer) and occurrence) and scattered and reflected) and ratio and determin\$4) and 250/\$.ccls.	· -	2003/05/16 16:21
18		(inspect\$3 near9 wafer) and occurrence near2 defect	US-PGPUB; EPO; JPO;	2003/05/16 16:21
19		((inspect\$3 near9 wafer) and occurrence near2 defect) and 356/\$.ccls.	DERWENT; IBM_TDB USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2003/05/16 16:22

L Numbe	r. Hit	s Search Text		
2			DB	Time stamp
. 2	100	3 ratio near2 (light near intensities)	USPAT:	2003/05/16 16:59
			US-PGPUB;	10.09
1			EPO; JPO;	
			DERWENT;	
3	790	6 inspection and scanner	IBM_TDB	
		- inspection and scannel	USPAT;	2003/05/16 17:11
1			US-PGPUB;	
•			EPO; JPO;	
			DERWENT;	;
1		•	IBM TDB	· †
1	1	2 multiple near light near optics	USPAT;	2003/05/16 17:00
		•	US-PGPUB;	2003/03/10 17:00
			EPO; JPO;	
1				
i	•		DERWENT;	
1 4	1	9 (ratio poor? /light many into the	IBM_TDB	
ļ ⁻		(ratio near2 (light near intensities)) and	USPAT;	2003/05/16 17:03
		(inspection and scanner)	US-PGPUB;	
1			EPO; JPO;	
			DERWENT;	
			IBM TDB	
5	; 8	(ratio near2 (light near intensities)) and	USPAT;	2003/05/16 17:05
i	ł	356/237.1	US-PGPUB;	2003/03/16 17:05
Ì	i		EDO: TDO	
	t .		EPO; JPO;	1
			DERWENT;	
6	101	(inspection and assure)	IBM_TDB	1
1	101	(inspection and scanner) and 356/237.1	USPAT;	2003/05/16 17:08
1	1		US-PGPUB;	1
1	;		EPO; JPO;	1
į			DERWENT;	
1	1	t	IBM TDB	
. 7	1 88	(inspection and scanner) and 356/237.5	USPAT;	2003/05/16 17:08
1	1	1	US-PGPUB;	2003/03/16 17:08
1				
!	1		EPO; JPO;	
•	1	i	DERWENT;	
8	10	linenect\$3 noar2 defect - 11 / 11	IBM_TDB	
	1	inspect\$3 near2 defect and (ratio near2	USPAT;	2003/05/16 17:13
!		(light near intensities))	US-PGPUB;	
			EPO; JPO;	
<u> </u>	,		DERWENT;	
	•	1	IBM TDB	,
9	50	(inspect\$3 near3 wafer) and (detect\$3	USPAT;	2003/05/16 17:15
		near6 (scatter\$3 and reflect\$3))	US-PGPUB;	2003/03/10 17:15
	:	1022000,		
	j	•	EPO; JPO;	1
	,	<u>,</u>	DERWENT;	į į
10	1		IBM_TDB	i
	l	<u> </u>	USPAT	2003/05/16 17:19